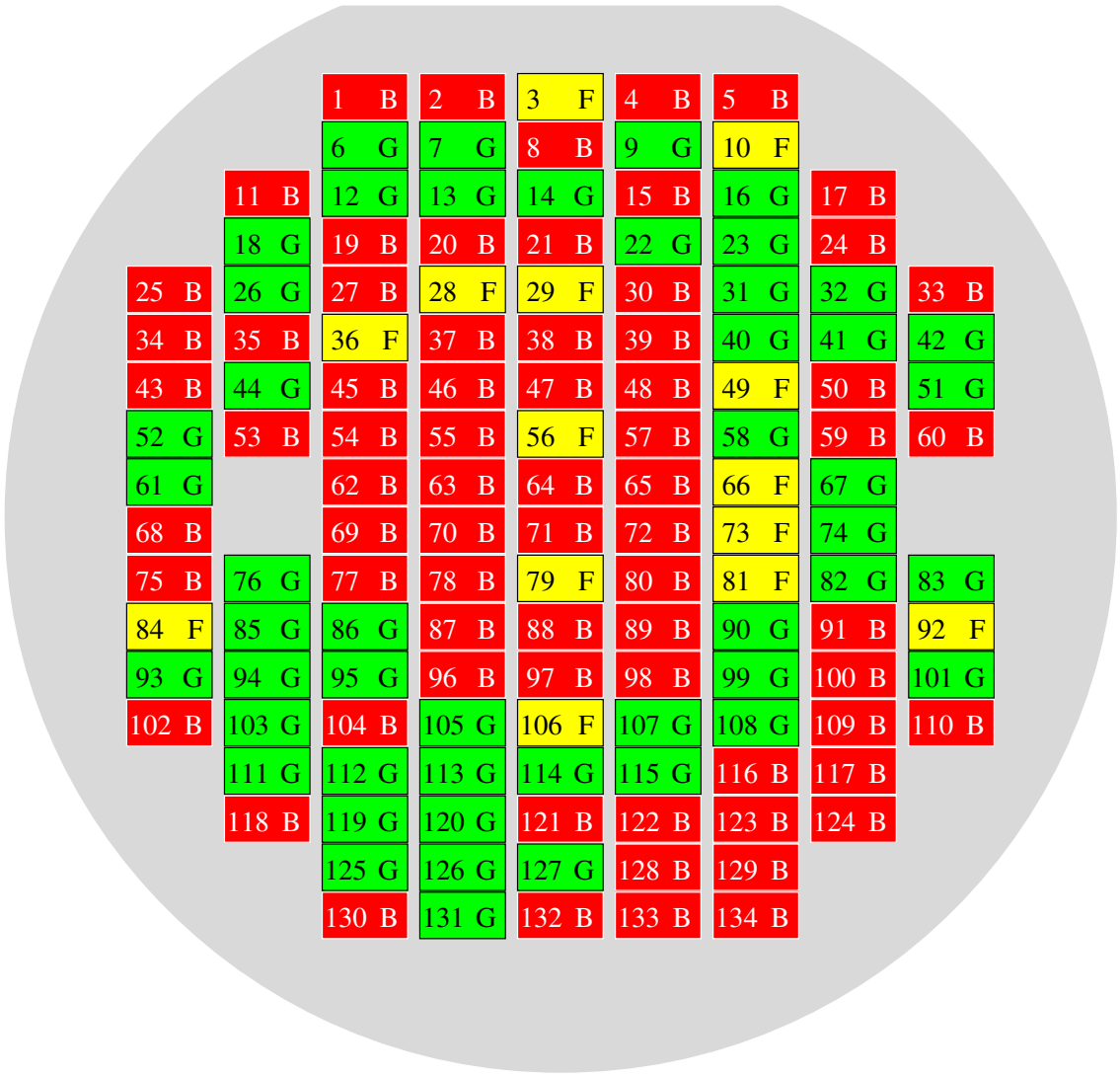
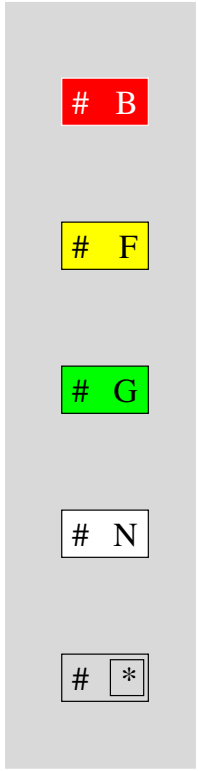
Die quality map for wafer 173 s/n: Y21316-09-18

Date: 07/07/99





Bad die

Fair die

Good die

No info

Manually tagged